

**Notice of References Cited**

Application/Control No.

09/406,663

Applicant(s)/Patent Under

Reexamination

KNEBEL ET AL.

Examiner

Fred Ferris

Art Unit

2128

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*	X	"An Integrated Photon Emission Microscope and MOSFET Characterization System of Combined Microscopic and Macroscopic Device Analysis", T.H. Ng, IEEE Proceedings fo 7 <sup>th</sup> IPFA '99, August 1999

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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*	V	"Picosecond Imaging Circuit Analysis of the POWER3 Clock Distribution", P.N. Sandra, 1999 IEEE International Solid-State Conference, June 1999.
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